

Brief Biography - Reza Zoughi, Ph.D.

R. Zoughi received his B.S.E.E, M.S.E.E, and Ph.D. degrees in electrical engineering (radar remote sensing, radar systems, and microwaves) from the University of Kansas where from 1981 until 1987 he was at the Radar Systems and Remote Sensing Laboratory (RSL). Currently he is the *Schlumberger Endowed Professor* of Electrical and Computer Engineering at Missouri University of Science and Technology (Missouri S&T), formerly University of Missouri-Rolla (UMR). Prior to joining Missouri S&T in January 2001 and since 1987 he was with the Electrical and Computer Engineering Department at Colorado State University (CSU), where he was a professor and established the Applied Microwave

Nondestructive Testing Laboratory (*amntl*) (<http://amntl.mst.edu/>). Dr. Zoughi held the position of *Business Challenge Endowed Professor* of Electrical and Computer Engineering from 1995 to 1997 while at CSU. Dr. Zoughi has been very active professionally serving his profession in many different capacities over the years. He has organized several American Society for Nondestructive Testing (ASNT) and Review of Progress in Quantitative Nondestructive Evaluation (QNDE) Conference sessions on the topic microwave and millimeter wave NDE, and two ASNT Post Conference Seminars (1992 and 2001). He served as the Editor-in-Chief of the *IEEE Transactions on Instrumentation and Measurement*, from 2007 through 2011, two terms as an at-large AdCom member of the IEEE Instrumentation and Measurement (I&M) Society, currently serves as the society's President and an I&M Society Distinguished Lecturer. He is the author of a textbook entitled "*Microwave Nondestructive Testing and Evaluation Principles*" KLUWER Academic Publishers, 2000, and the co-author of a chapter on Microwave Techniques in the book entitled "*Nondestructive Evaluation: Theory, Techniques, and Applications*" Marcel and Dekker, Inc., 2002. He has been the recipient of numerous teaching awards both at CSU and Missouri S&T. He is the recipient of the 2007 IEEE Instrumentation and Measurement Society *Distinguished Service Award*, the 2009 American Society for Nondestructive Testing (ASNT) *Research Award for Sustained Excellence* and the 2011 IEEE *Joseph F. Keithley Award in Instrumentation and Measurement*. He is the co-author of over 541 journal papers, conference proceedings and presentations and technical reports. He has thirteen patents to his credit all in the field of microwave nondestructive testing and evaluation. He has delivered numerous *Invited* and *Keynote* presentations on the subject of microwave and millimeter wave NDT and imaging. He is also a *Fellow* of the American Society for Nondestructive Testing (ASNT) and a *Fellow* of the Institute of Electrical and Electronics Engineers (IEEE).